

# Resource Summary Report

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## Anton Paar: NHT3 Nanoindentation Tester

RRID:SCR\_024829

Type: Tool

### Proper Citation

Anton Paar: NHT3 Nanoindentation Tester (RRID:SCR\_024829)

### Resource Information

**URL:** <https://www.anton-paar.com/corp-en/products/details/nanoindentation-tester-nht3/?srsltid=AfmBOoq6DedA15vEkZb-PLCzHLAhmUbyxAtnWW50jyljVyQCds0yZOPP>

**Proper Citation:** Anton Paar: NHT3 Nanoindentation Tester (RRID:SCR\_024829)

**Description:** Used for testing hardness, elastic modulus, creep and other surface properties at nanometer to micrometer scale. Its range is from 0.1 mN to 500mN with no need to wait to reach thermal stable state, and instrument indentation test can be performed immediately after startup.NHT3 is a versatile, research-grade platform suited for highly customizable mechanical surface testing.

**Synonyms:** NHT?? Nanoindentation Tester

**Resource Type:** instrument resource

**Keywords:** testing hardness, testing elastic modulus, surface properties testing, testing at nanometer to micrometer scale,

**Availability:** Commercially available

**Specification URL:** [https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR\\_024829.pdf](https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_024829.pdf)

**Resource Name:** Anton Paar: NHT3 Nanoindentation Tester

**Resource ID:** SCR\_024829

**Alternate IDs:** Model\_Number\_NHT3

**Old URLs:** <https://www.anton-paar.cn/products/details/nanoindentation-tester-nht3/>

**Record Creation Time:** 20240104T050329+0000

**Record Last Update:** 20260829T183346+0000

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## Ratings and Alerts

No rating or validation information has been found for Anton Paar: NHT3 Nanoindentation Tester.

No alerts have been found for Anton Paar: NHT3 Nanoindentation Tester.

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## Data and Source Information

**Source:** [SciCrunch Registry](#)

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## Usage and Citation Metrics

We found 1 mentions in open access literature.

**Listed below are recent publications.** The full list is available at [NIF](#) .

Zhang Y, et al. (2024) Penetrating the ultra-tough yeast cell wall with finite element analysis model-aided design of microtools. iScience, 27(4), 109503.